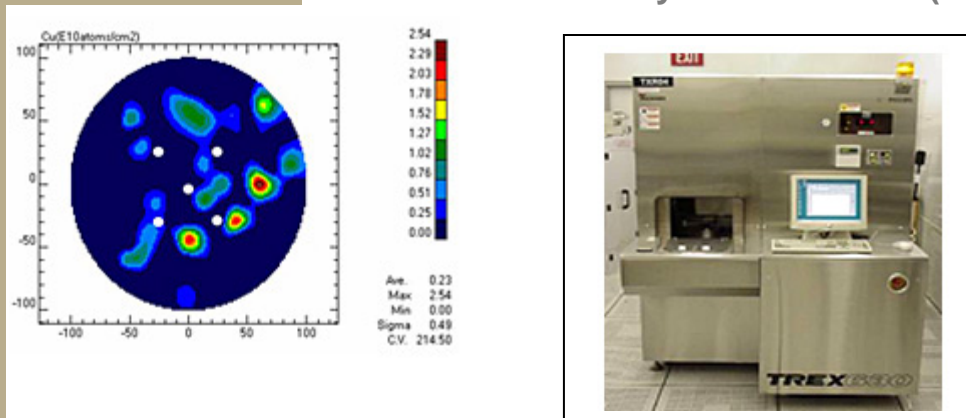


Total Reflection X-ray Fluorescence (TXRF)



Total Reflection X-ray Fluorescence (TXRF)



Instruments

- Technos 630T - Tungsten and Silver Anodes (200/300mm wafers)

Applications

- Non-destructive analysis
- Spatial information on trace metal contamination
- Mapping of contamination (upper figure)

Technical Specifications

- 1cm diameter spot size
- Detection limits in the mid E09 - low E10 atoms/cm² range

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